



STC6NF30V

N-CHANNEL 30V - 0.020 Ω - 6A TSSOP8 2.5V-DRIVE STripFET™ II POWER MOSFET

TYPE	V _{DSS}	R _{DS(on)}	I _D
STC6NF30V	30 V	< 0.025 Ω (@ 4.5 V) < 0.030 Ω (@ 2.5 V)	6 A

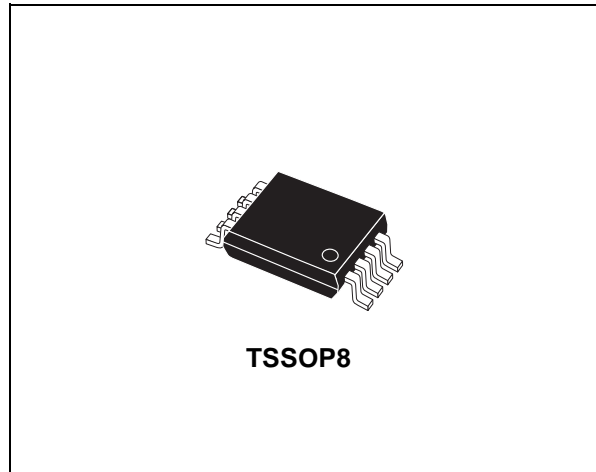
- TYPICAL R_{DS(on)} = 0.020 Ω @ 4.5 V
- TYPICAL R_{DS(on)} = 0.025 Ω @ 2.5 V
- ULTRA LOW THRESHOLD GATE DRIVE (2.5 V)
- STANDARD OUTLINE FOR EASY AUTOMATED SURFACE MOUNT ASSEMBLY
- DOUBLE DICE IN COMMON DRAIN CONFIGURATION

DESCRIPTION

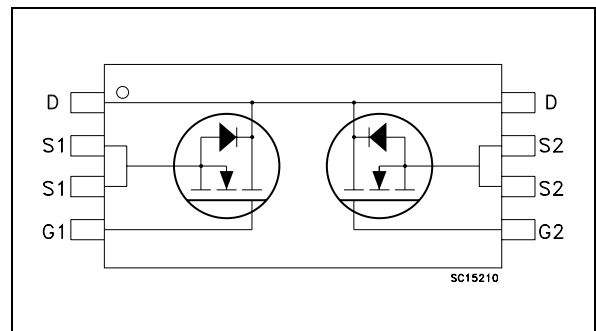
This Power MOSFET is the latest development of STMicroelectronics unique "Single Feature Size™" strip-based process. The resulting transistor shows extremely high packing density for low on-resistance.

APPLICATIONS

- DC MOTOR DRIVE
- DC-DC CONVERTERS
- BATTERY SAFETY UNIT FOR NOMADIC EQUIPMENT
- POWER MANAGEMENT IN PORTABLE/DESKTOP PCs



INTERNAL SCHEMATIC DIAGRAM



ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source Voltage (V _{GS} = 0)	30	V
V _{DGR}	Drain-gate Voltage (R _{GS} = 20 k Ω)	30	V
V _{GS}	Gate- source Voltage	± 12	V
I _D	Drain Current (continuous) at T _C = 25°C	6	A
I _D	Drain Current (continuous) at T _C = 100°C	3.8	A
I _{DM} (●)	Drain Current (pulsed)	24	A
P _{tot}	Total Dissipation at T _C = 25°C	1.5	W

(●) Pulse width limited by safe operating area.

STC6NF30V

THERMAL DATA

Rthj-pcb	Thermal Resistance Junction-PCB (**)	Max	100	°C/W
Rthj-pcb	Thermal Resistance Junction-PCB (*)	Max	83.5	°C/W
T _j	Operating Junction Temperature		-55 to 150	°C
T _{stg}	Storage temperature		-55 to 150	°C

(*) When Mounted on FR-4 board with 1 inch² pad, 2 oz of Cu and t ≤ 10 sec

(**) When Mounted on minimum recommended footprint

ELECTRICAL CHARACTERISTICS (T_j = 25 °C unless otherwise specified)

OFF

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown Voltage	I _D = 250 μA, V _{GS} = 0	30			V
I _{DSS}	Zero Gate Voltage Drain Current (V _{GS} = 0)	V _{DS} = Max Rating V _{DS} = Max Rating T _C = 125°C			1 10	μA μA
I _{GSS}	Gate-body Leakage Current (V _{DS} = 0)	V _{GS} = ± 12 V			±100	nA

ON (*)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} I _D = 250 μA	0.6			V
R _{DS(on)}	Static Drain-source On Resistance	V _{GS} = 4.5 V I _D = 3 A V _{GS} = 2.5 V I _D = 3 A		0.020 0.025	0.025 0.030	Ω Ω

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
g _{fs} (*)	Forward Transconductance	V _{DS} = 10 V I _D = 6 A		18		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V _{DS} = 25V f = 1 MHz, V _{GS} = 0		800 180 32		pF pF pF

ELECTRICAL CHARACTERISTICS (continued)

SWITCHING ON

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$ t_r	Turn-on Delay Time Rise Time	$V_{DD} = 15\text{ V}$ $I_D = 3\text{ A}$ $R_G = 4.7\ \Omega$ $V_{GS} = 2.5\text{ V}$ (Resistive Load, Figure 1)		20 25		ns ns
Q_g Q_{gs} Q_{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	$V_{DD} = 15\text{ V}$ $I_D = 6\text{ A}$ $V_{GS} = 2.5\text{ V}$ (see test circuit, Figure 2)		6.8 2.0 3.4	9	nC nC nC

SWITCHING OFF

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_{d(off)}$ t_f	Turn-off Delay Time Fall Time	$V_{DD} = 15\text{ V}$ $I_D = 3\text{ A}$ $R_G = 4.7\ \Omega$, $V_{GS} = 2.5\text{ V}$ (Resistive Load, Figure 1)		32 13		ns ns

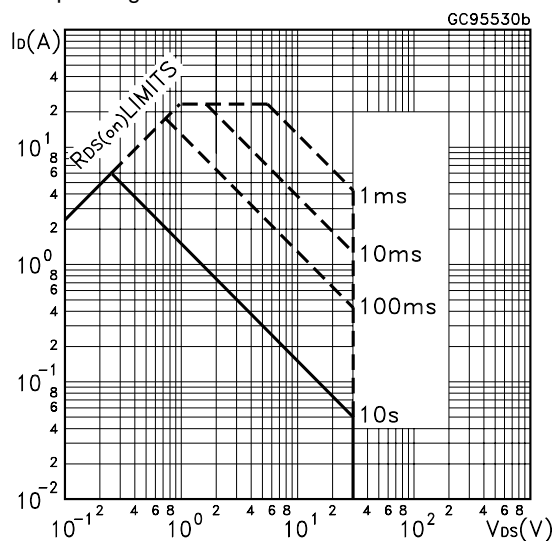
SOURCE DRAIN DIODE

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
I_{SD} $I_{SDM} (\bullet)$	Source-drain Current Source-drain Current (pulsed)				6 24	A A
$V_{SD} (*)$	Forward On Voltage	$I_{SD} = 6\text{ A}$ $V_{GS} = 0$			1.2	V
t_{rr} Q_{rr} I_{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 6\text{ A}$ $di/dt = 100\text{ A}/\mu\text{s}$ $V_{DD} = 15\text{ V}$ $T_j = 150^\circ\text{C}$ (see test circuit, Figure 3)		25 21 1.7		ns nC A

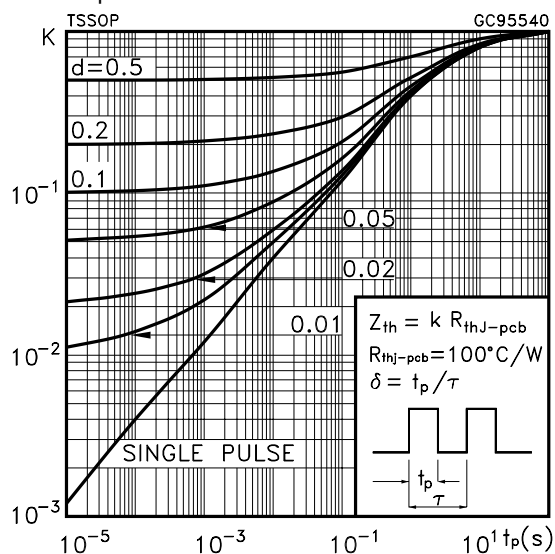
(*) Pulsed: Pulse duration = 300 μs , duty cycle 1.5 %.

(\bullet) Pulse width limited by safe operating area.

Safe Operating Area.

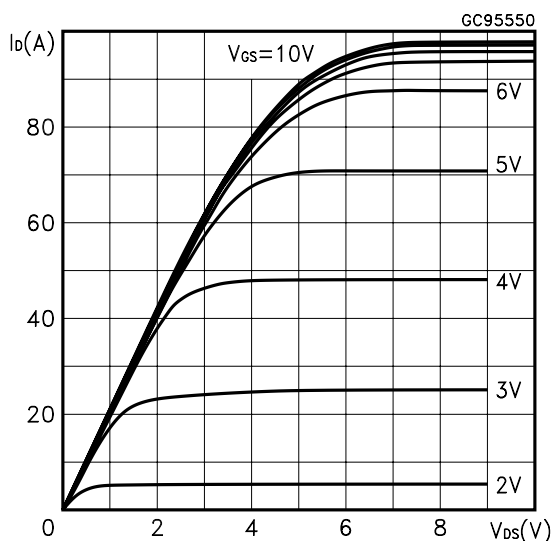


Thermal Impedance.

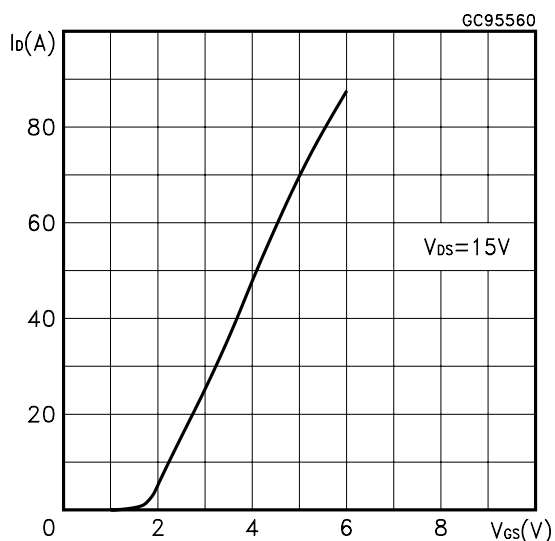


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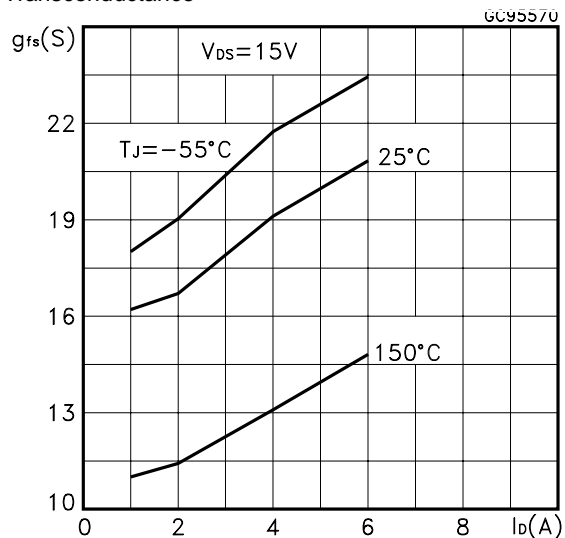
Output Characteristics



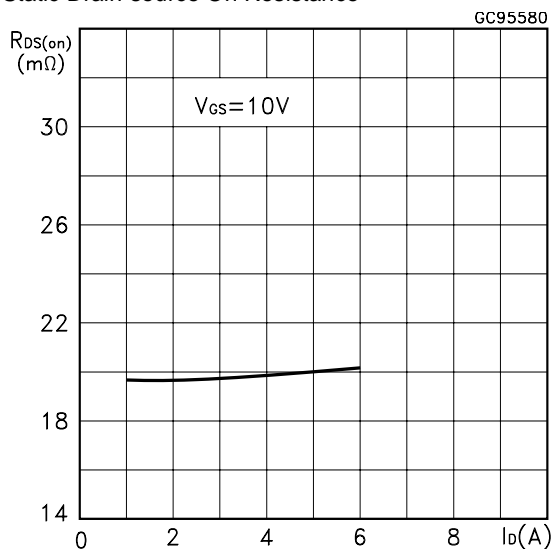
Transfer Characteristics



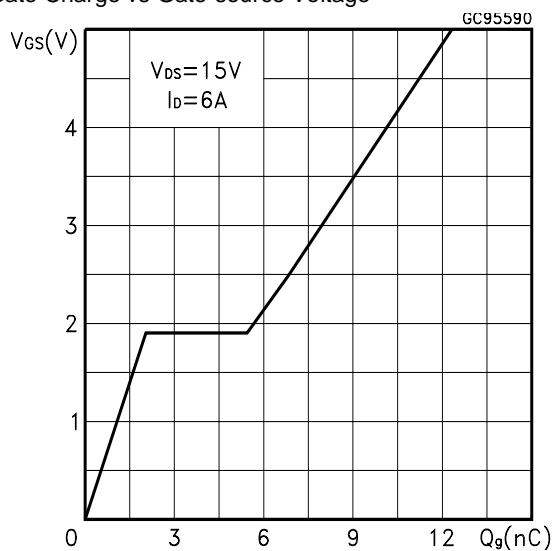
Transconductance



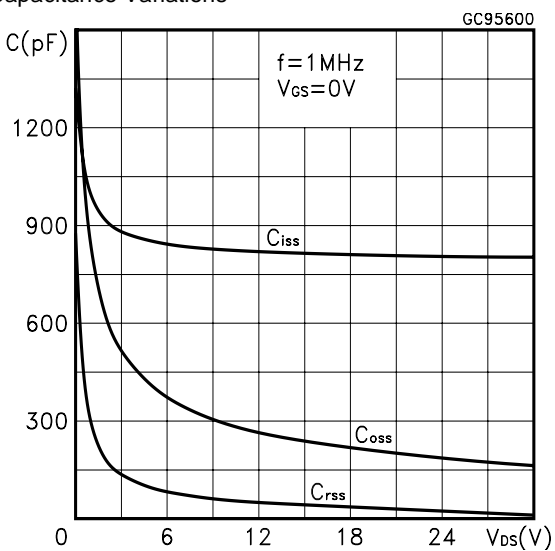
Static Drain-source On Resistance



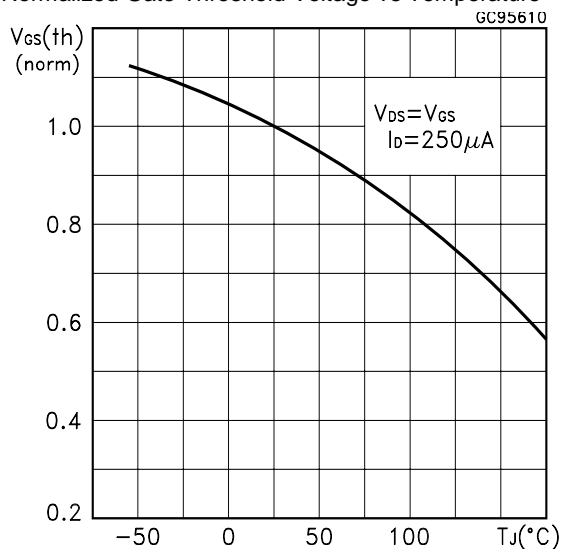
Gate Charge vs Gate-source Voltage



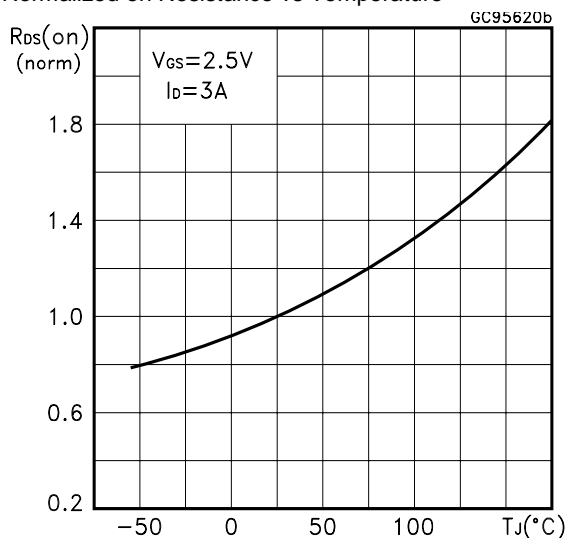
Capacitance Variations



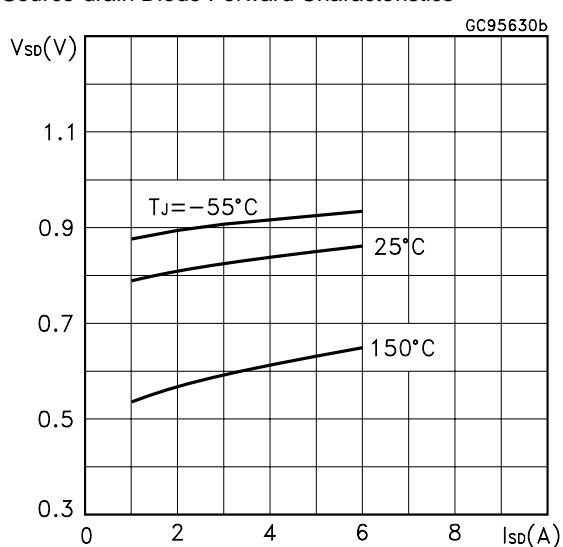
Normalized Gate Threshold Voltage vs Temperature



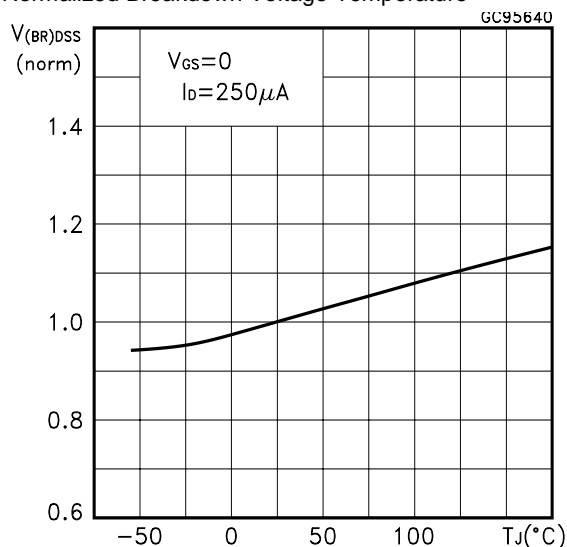
Normalized on Resistance vs Temperature



Source-drain Diode Forward Characteristics



Normalized Breakdown Voltage Temperature



Thermal resistance and max power

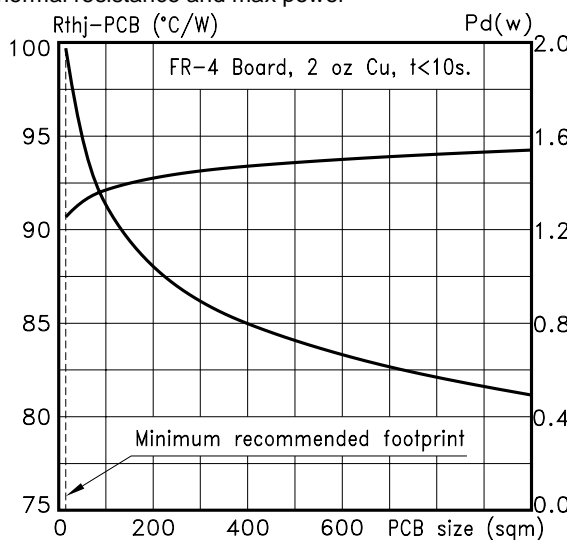


Fig. 1: Switching Times Test Circuits For Resistive Load

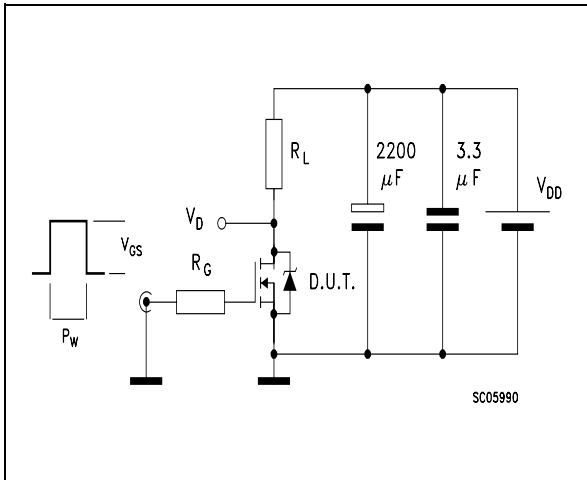


Fig. 2: Gate Charge test Circuit

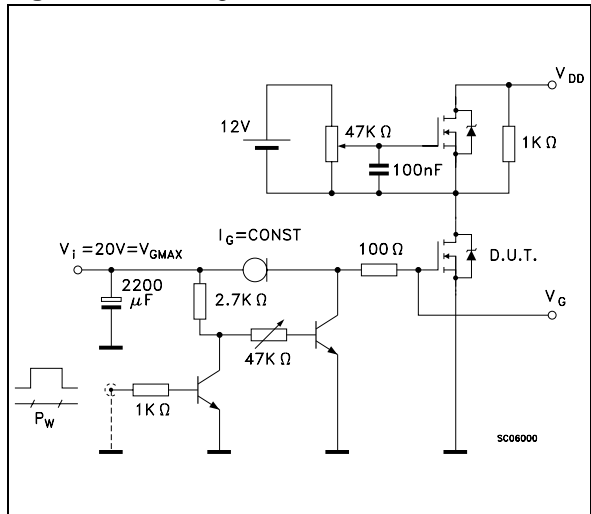
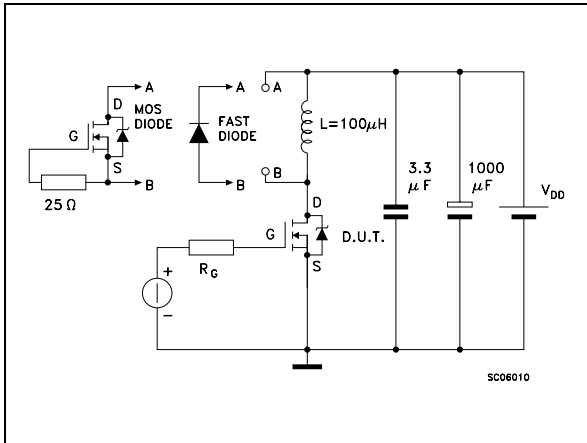
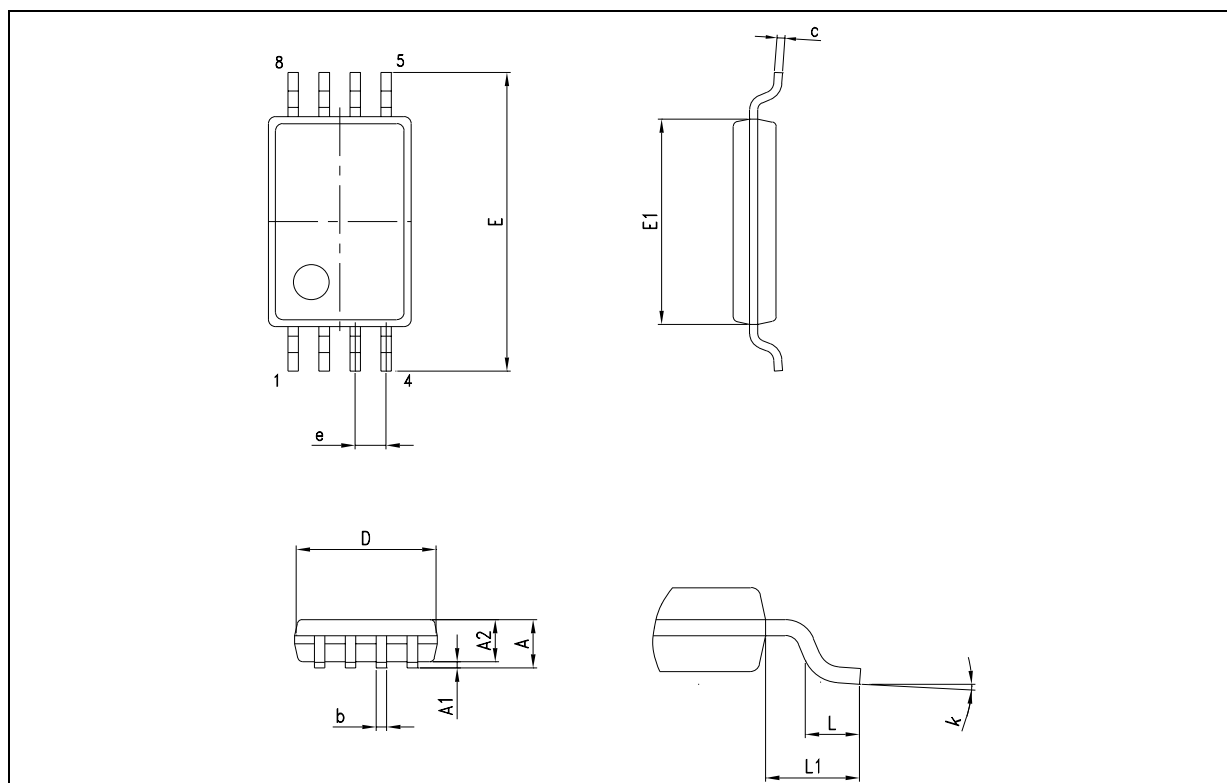


Fig. 3: Test Circuit For Diode Recovery Behaviour



TSSOP8 MECHANICAL DATA

DIM.	mm.			inch.		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A	1.05		1.20	0.041		0.047
A1	0.05		0.15	0.002		0.006
A2	0.80		1.05	0.032		0.041
b	0.19		0.30	0.008		0.012
c	0.090		0.20	0.003		0.007
D	2.90		3.10	0.114		0.122
E	6.20		6.60	0.240		0.260
E1	4.30		4.50	0.170		0.177
e		0.65			0.025	
L	0.45		0.75	0.018		0.030
L1		1.00			0.039	
k	0°		8°	0.192		0.208



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